

Search Notes				Application No.	Applicant(s)	
				10/706,090	SUGAMOTO ET AL.	
				Examiner	Art Unit	
				Granvill D Lee, Jr	2825	

SEARCHED			
Class	Subclass	Date	Examiner
438	745,689	9/1/2004	GL
438	693,704	9/1/2004	GL
438	494,498	9/1/2004	GL
438	504	9/1/2004	GL
438	734-735	9/1/2004	GL
216	56,62	9/1/2004	GL
216	103-109	9/1/2004	GL
156	345.1	9/1/2004	GL
156	345.11	9/1/2004	GL
156	912-915	9/1/2004	GL
Above	Warded	3/16/2005	GL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
second solution, oxidative acid, oxidizing agent, crystal defects, secco etch, cleaning, selective etching, HF, defect-free	9/1/2004	GL
UPDATED See EAST	3/16/2005	Q

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner